Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/631,119	MAUCERI ET AL.	
Examiner	Art Unit	
Quoc A. Tran	2176	

SEARCHED					
Class	Subclass	Date	Examiner		
715	513	8/24/2005	D)		
707	102	8/24/2005	8		
715	517	8/24/2005	8)/		
345	440	8/24/2005	$\langle \chi \rangle$		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
INVENTORS SEARCH CHECK FOR DOUBLE PATENT	8/24/2005	#		
EAST (US-PAT, US-PGPUB, EPO, JPO, DERWENT, IBM_TDBSee Search Histoty Printout	8/24/2005	W		
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